

Notice of References Cited

Application/Control No.

10/817,287

Applicant(s)/Patent Under
Reexamination
LIU ET AL.

Examiner

AFROZA Y. CHOWDHURY

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0196266	10-2004	Matsuura et al.	345/169
*	B	US-6,724,370	04-2004	Dutta et al.	345/169
*	C	US-6,424,743	07-2002	Ebrahimi, Ali	382/189
*	D	US-7,002,560	02-2006	Graham, Evan	345/179
*	E	US-2004/0263486	12-2004	Seni, Giovanni	345/173
*	F	US-2004/0036680	02-2004	Davis et al.	345/169
*	G	US-2002/0190957	12-2002	Lee et al.	345/169
*	H	US-6,839,464	01-2005	Hawkins et al.	382/187
*	I	US-2005/0057520	03-2005	Robinson, Robert J.	345/169
*	J	US-7,113,178	09-2006	Webb, Russell Y.	345/173
*	K	US-5,778,404	07-1998	Capps et al.	715/234
*	L	US-6,661,409	12-2003	Demartines et al.	345/173
*	M	US-5,655,136	08-1997	Morgan, Michael W.	382/187

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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